In 2015, the SERE conference (IEEE International Conference on Software Security and Reliability) and the QSIC conference (IEEE International Conference on Quality Software) were combined into a single conference, QRS, with Q representing Quality, R for Reliability, and S for Security, sponsored by the IEEE Reliability Society. This conference provides engineers and scientists from both industry and academia a platform to present their ongoing work, relate their research outcomes and experiences, and discuss the best and most efficient techniques for the development of reliable, secure, and trustworthy systems. It also represents an excellent opportunity for the academic community to become more aware of subject areas critical to the software industry as practitioners bring their needs to the table. The 20th QRS conference will be held from December 11-14 in Macau, China.

**TOPICS OF INTEREST**

- Reliability, Security, Availability, and Safety of Software Systems
- Software Testing, Verification, and Validation
- Program Debugging and Comprehension
- Information and Software Quality Assurance
- Fault Tolerance for Software Reliability Improvement
- Modeling, Prediction, Simulation, and Evaluation
- Metrics, Measurements, and Analysis
- Secure and Reliable Storage
- Software Penetration and Protection
- Software Vulnerabilities
- Formal Methods
- Malware Detection and Analysis
- Intrusion Detection and Prevention
- Operating System Security and Reliability
- Mobile and Smartphone Applications
- Internet of Things and Cloud Computing
- Information and Knowledge Management
- Benchmark, Tools, Industrial Applications, and Empirical Studies
- Machine Learning and Deep Learning Models and Systems

**IMPORTANT DATES**

- April 10, 2020: Regular and Short papers due
- June 15, 2020: Workshop papers due
- June 15, 2020: Fast Abstracts, Industry Track, and Posters due
- July 1, 2020: Author Notification (Regular and Short)
- July 10, 2020: Author Notification (Workshop, Fast Abstract, Industry Track, and Poster)

**SUBMISSION**

Submit original manuscripts (not published or considered elsewhere) with the following page maximums: twelve pages (regular papers), eight pages (short papers and workshop papers), and two pages (Fast Abstracts Track and Industry Track). Each paper should include a title and the name and affiliation of each author. Except for the Fast Abstracts Track and Industry Track, each submission should also include a 150-word abstract and up to 6 keywords. The format of your submission must follow the guidelines for IEEE conference proceedings. At least one Best Paper Award with a cash prize will be presented. Detailed instructions for paper submission can be found at https://qrs.techconf.org.

**CONFERENCE PROCEEDINGS & SPECIAL SECTION OF IEEE TRANSACTIONS ON RELIABILITY**

IEEE Computer Society Conference Publishing Services (CPS) will publish the proceedings. Accepted papers will also be submitted for inclusion in the IEEE Xplore and to other abstracting and indexing partners such as the Ei Compendex. Selected papers of top quality will be published in a special section of IEEE Transactions on Reliability instead of the conference proceedings. This will speed up the journal publication of these papers. There is also a special section of IEEE Access for extended versions of high quality papers from QRS.

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For more detailed and updated information, please refer to https://qrs.techconf.org. For paper submission, review, or other questions, please send emails to qrsconference@outlook.com.